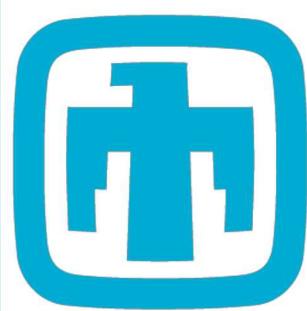


A Physically Unclonable Function (PUF) Using Micromagnets and NV Magnetic Imaging

Pauli Kehayias, Ezra Bussmann, Tzu-Ming Lu, Andrew Mounce



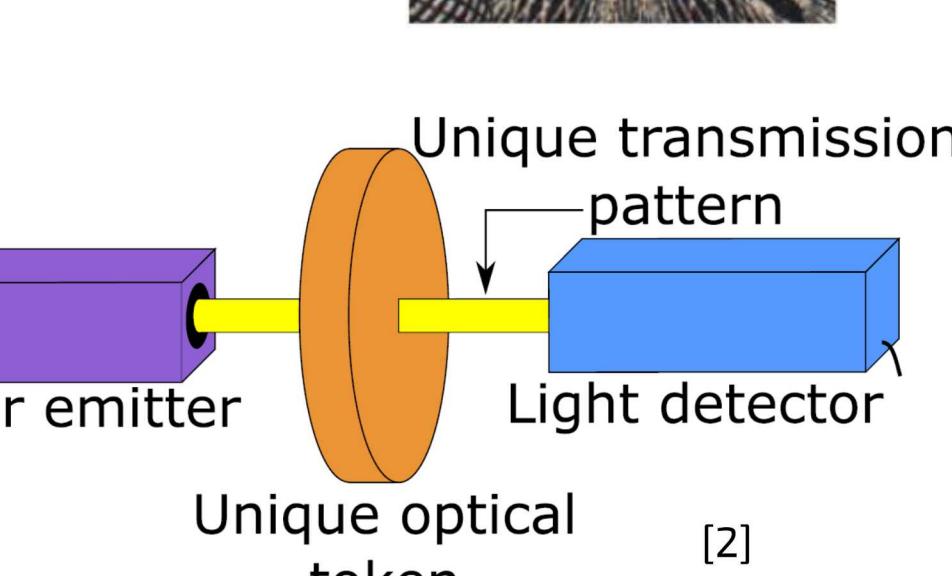
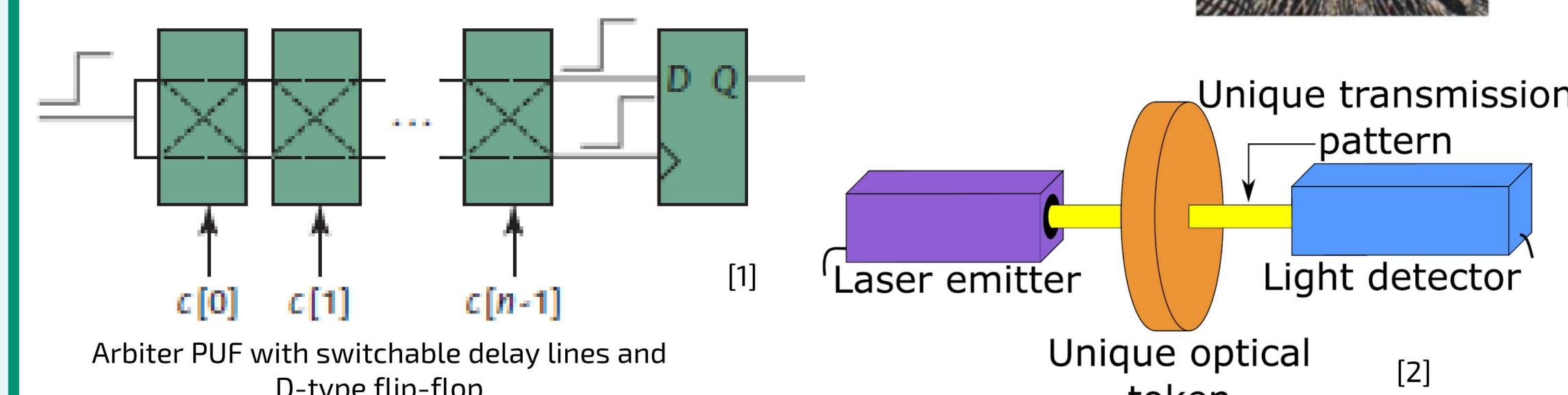
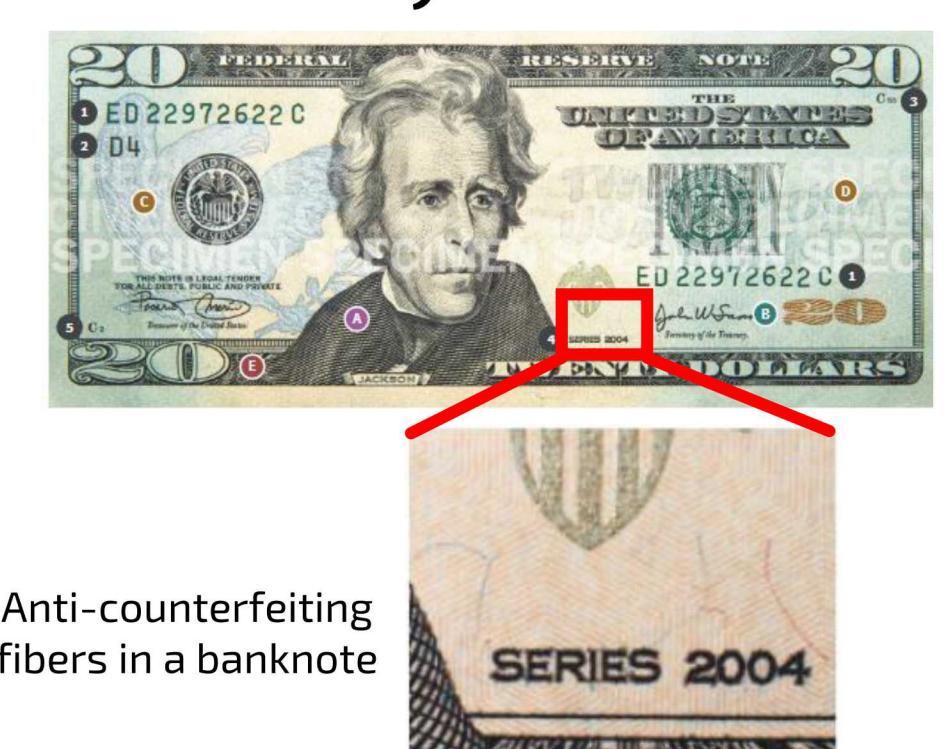
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Center for Integrated Nanotechnologies (CINT), Sandia National Laboratories, Albuquerque, NM



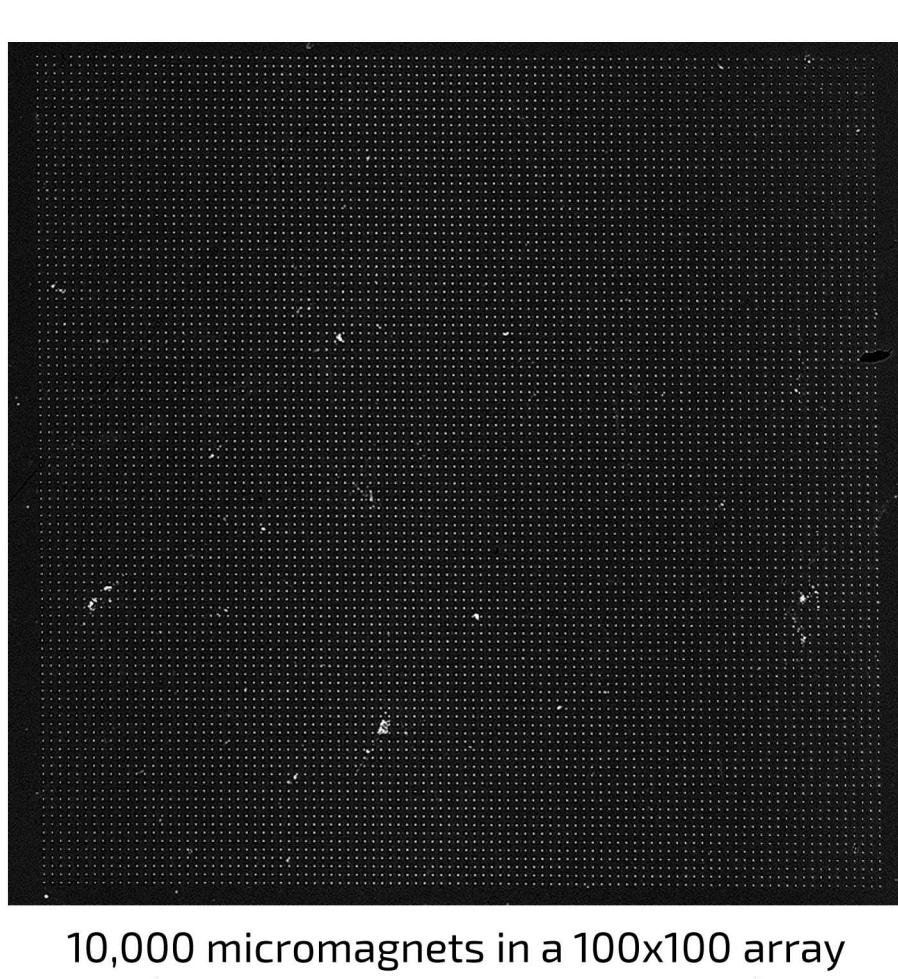
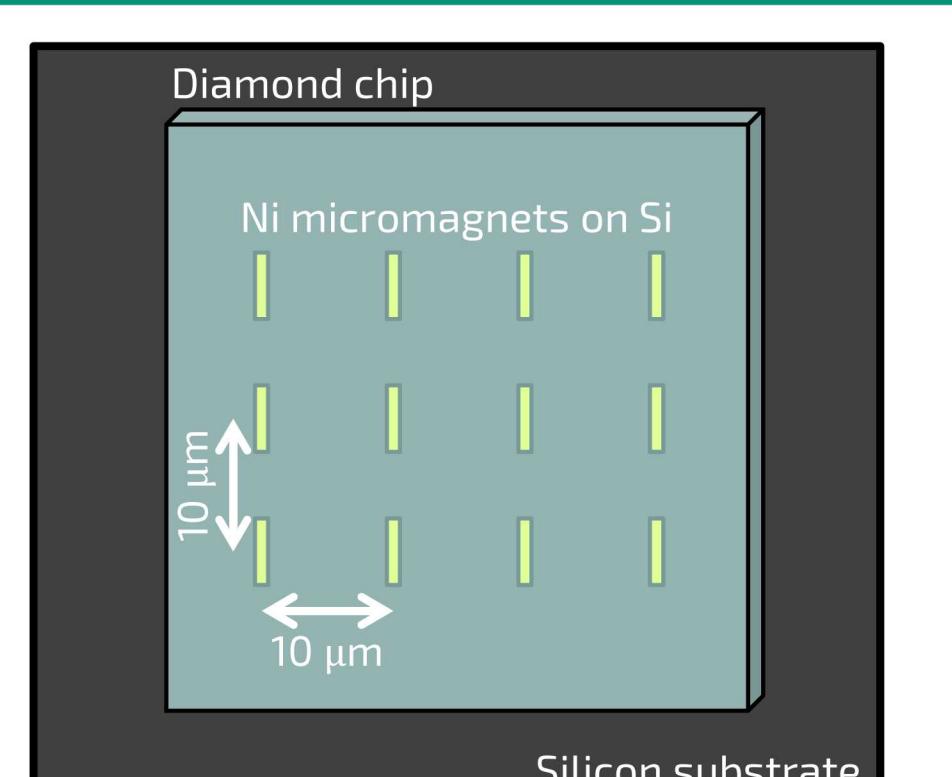
Introduction to PUFs

- Anti-counterfeiting hardware security measure
- Desired properties
 - Easy to produce
 - Difficult to duplicate
 - Easy & reproducible readout
 - Low-cost & resilient
- Our approach: fabricated array of ferromagnetic rods
 - Random magnetic moment orientations
 - NV diamond widefield magnetic imaging readout
 - Image analysis

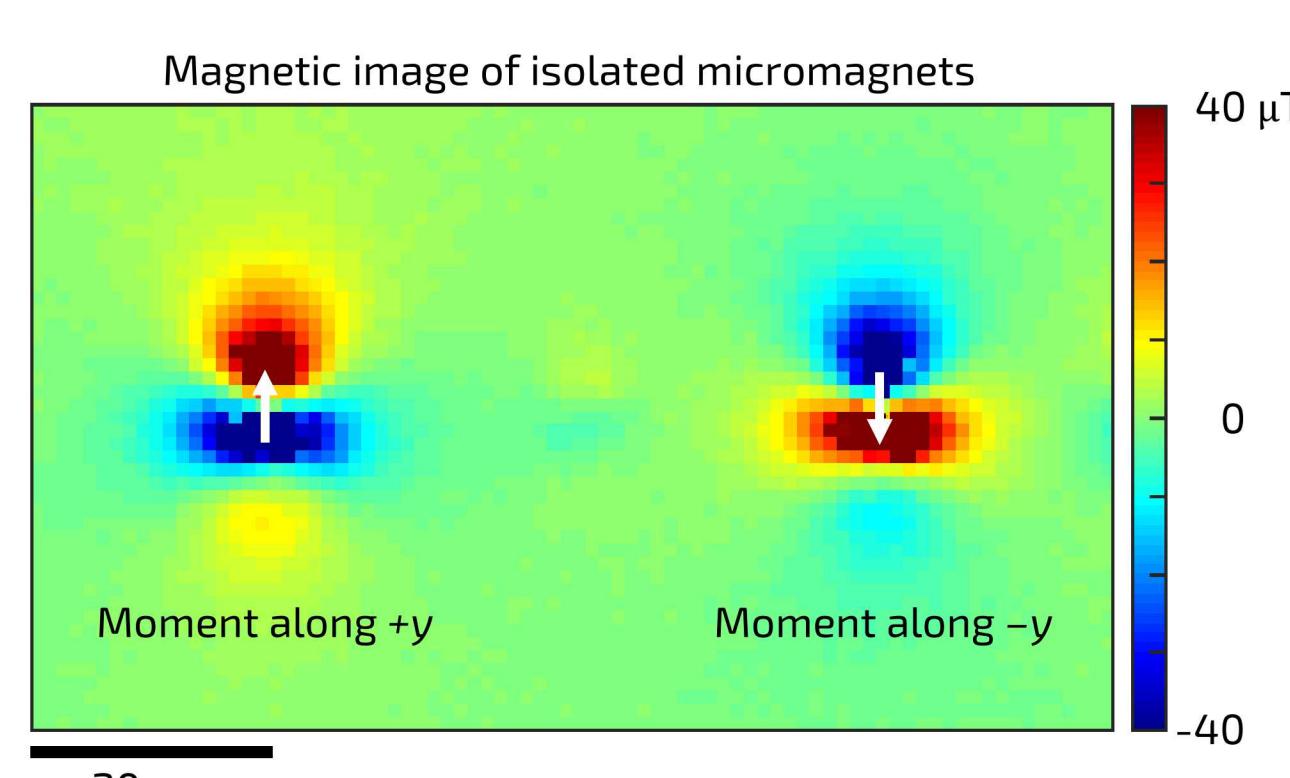


Micromagnet fabrication

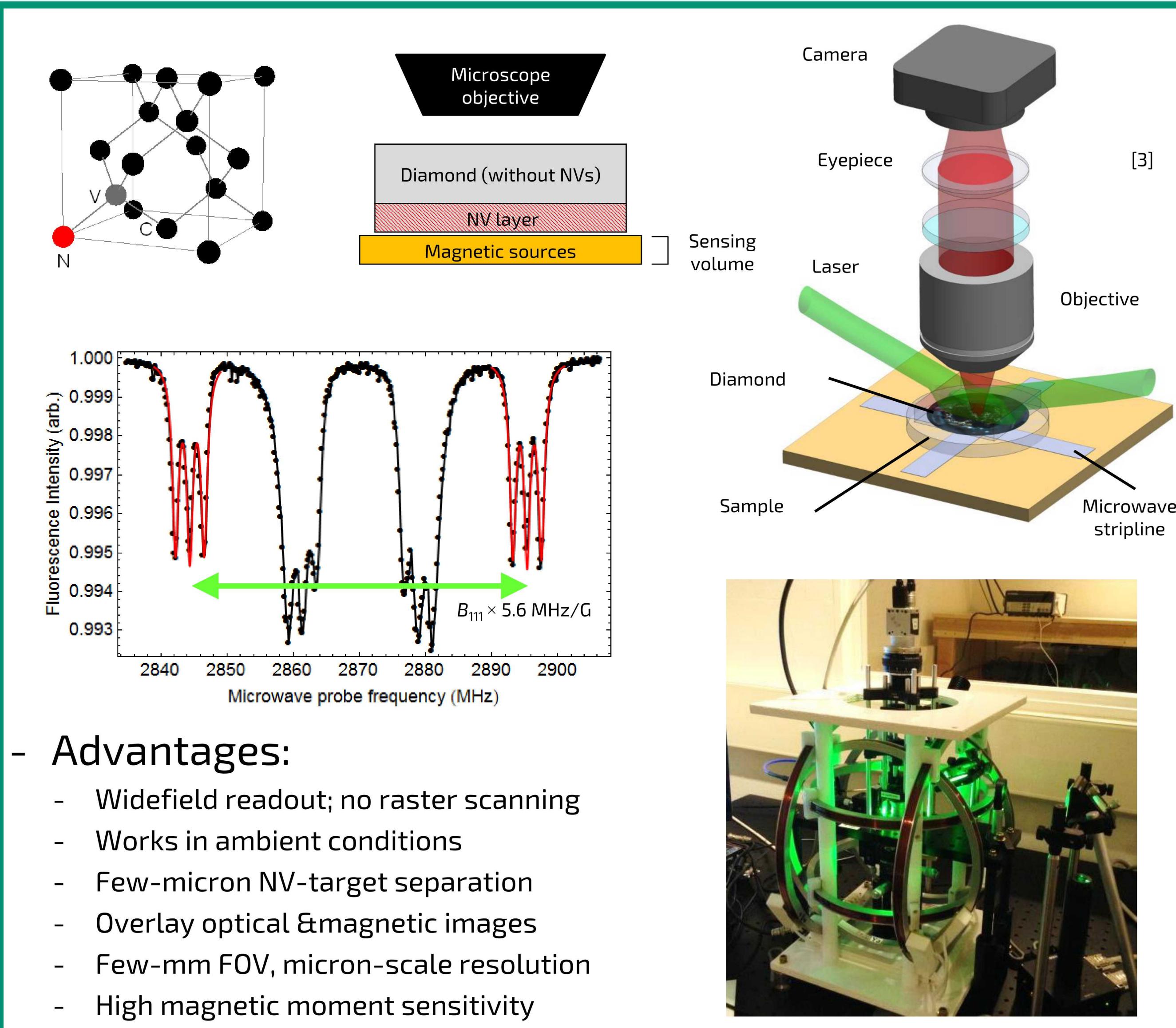
- Recipe:
 - e-beam lithography on resist
 - Develop
 - Nickel deposition
 - Lift-off
 - Al_2O_3 protective layer
- Rod-shaped micromagnets; easy axis along $\pm y$
- Dipole-like magnetic field map



10,000 micromagnets in a 100x100 array
(1 mm \times 1 mm, 4 μm \times 1 μm each)



NV magnetic microscopy



Advantages:

- Widefield readout; no raster scanning
- Works in ambient conditions
- Few-micron NV-target separation
- Overlay optical & magnetic images
- Few-mm FOV, micron-scale resolution
- High magnetic moment sensitivity
- Sensitive to deep sources

Example micromagnet PUF image

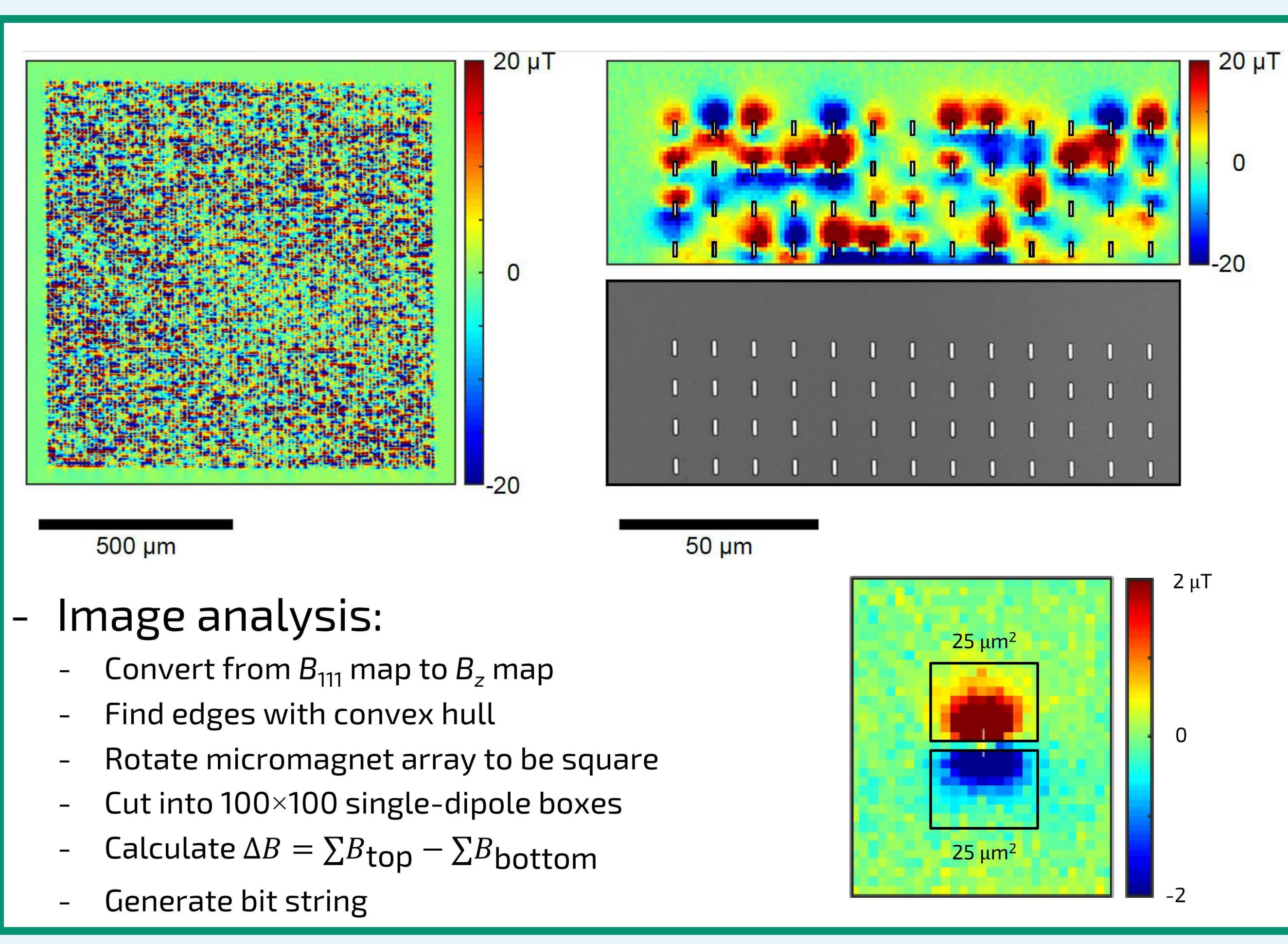
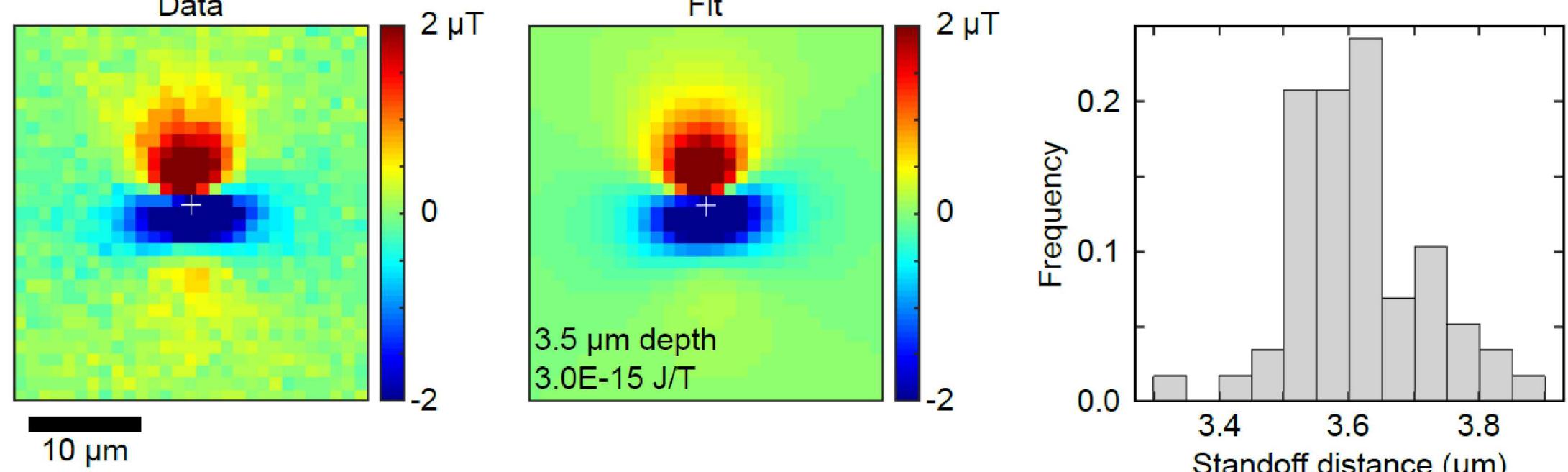


Image analysis:

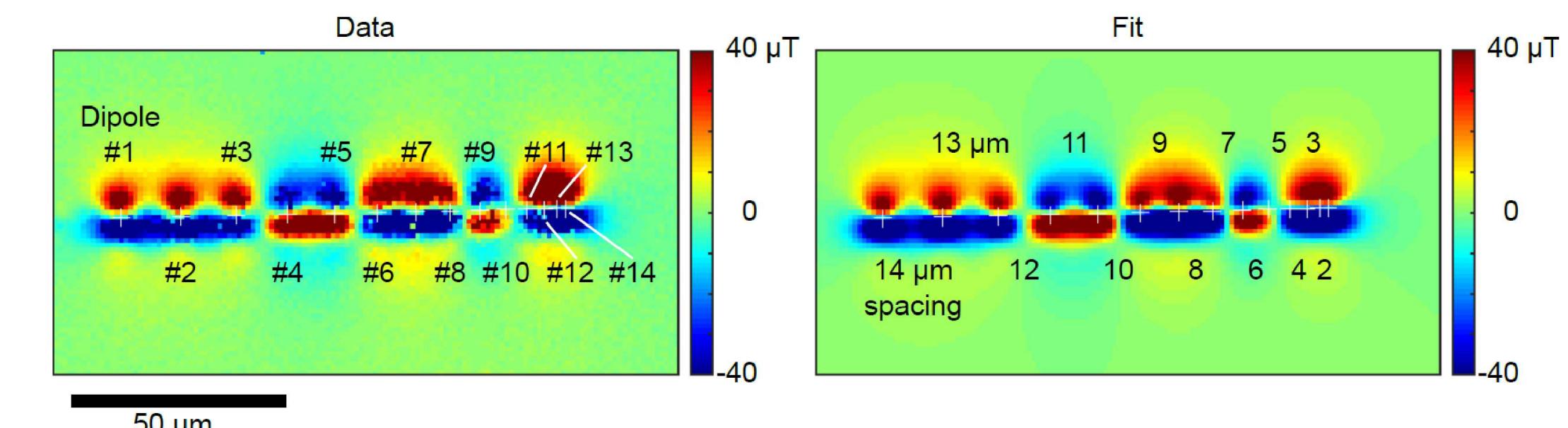
- Convert from B_{111} map to B_z map
- Find edges with convex hull
- Rotate micromagnet array to be square
- Cut into 100x100 single-dipole boxes
- Calculate $\Delta B = \sum B_{\text{top}} - \sum B_{\text{bottom}}$
- Generate bit string

Performance specs

- Up to few-second readout time
- 3.6 μm NV-micromagnet standoff distance



- Closest-resolvable separation is $\sim 5 \mu\text{m}$



- Passes most NIST randomness statistical tests

Statistical Test	p-value	Result	Comments
Frequency	0.023821	Pass	
Block Frequency	0.036802	Pass	
Runs	0.000000	Fail	Bit string values fluctuate too slowly
Longest Run	0.465732	Pass	
Rank	0.862457	Pass	
Discrete Fourier Transform	0.066457	Pass	
Non-Overlapping Template	-	-	138 out of 148 tests pass
Overlapping Template	0.241223	Pass	
Maurer's Universal	-	-	Too few bits to evaluate
Linear Complexity	0.543677	Pass	
Serial ($\nabla \psi_m^2$)	0.059629	Pass	
Serial ($\nabla^2 \psi_m^2$)	0.311516	Pass	
Approximate Entropy	0.000503	Fail	
Cumulative Sums Forward	0.027787	Pass	
Cumulative Sums Reverse	0.036550	Pass	
Random Excursions	-	-	Too few bits to evaluate
Random Excursions Variant	-	-	Too few bits to evaluate

Outlook

- Investigate materials, micromagnet dimensions, and NV layer thickness
- Characterize robustness to the environment

References

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2. T. McGrath et al., Appl. Phys. Rev. 6 011303 (2019)
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4. A. Rukhin et al., NIST Special Publication 800-22 Revision 1a (2010).
5. P. Kehayias et al., in prep. (2020).